

photon electrically driven light sources operating at room temperature  
3. Development of high–pressure, high–temperature diamond anvil cells with internally heated anvils for hydrothermal and shear stress experiments.

The instrument will also be used in courses on materials science. Application accepted by Commissioner of Customs: December 20, 2005.

Docket Number: 06–002. Applicant: The University of Puerto Rico at Mayaguez, Dept. Of Chemistry, Mayaguez, Puerto Rico 00680 Instrument: Electron Microscope, Model JEM–2010 Manufacturer: JEOL Ltd., Japan. Intended Use: The instrument is intended to be used for experimental studies including the characterization of gold and silver nanostructures, structure–property relations in semiconductor nanoparticles, nanowire formations and nanorods, structural fuel cell performance and the catalytic activity of Pt, Ru and Pt–Ru nanostructures, and the structure of functionalized organic–based nanofibers. The instrument will also be used in a variety of courses. Application accepted by Commissioner of Customs: January 20, 2006.

Docket Number: 06–003. Applicant: Oklahoma State University, 203 Whitehurst, Stillwater, OK 74048–3011. Instrument: Electron Microscope, Model JEM–2100F. Manufacturer: JEOL Ltd., Japan. Intended Use: The instrument is intended to be used for studies including:

1. Decomposed metal complexes at low temperatures which yield nanocrystalline products that are useful catalysts, electrode materials for batteries and supercapacitors, corrosion inhibitors, photovoltaics, and sorbants for pollutants.
2. Semiconducting nanoparticles (as small as 2 nm), single wall nanotubes and the electrical conductivity of either a semiconductor or a metal, depending on the diameter and helicity of the tube.
3. Virus–vector interactions in several important plant disease inducing viruses, that are vectored by fungi, for understanding emerging diseases in plants.

It will also be used for graduate student training in electron microscopy. Application accepted by Commissioner of Customs: January 23, 2006. Docket Number: 06–004. Applicant: University of North Texas, Department of Materials Science and Engineering,

3940 N. Elm, Research Park Room E132, Denton, TX 76203. Instrument: Mass Spectrometer, Model Nova 200 NanoLab. Manufacturer: FEI Company, The Netherlands. Intended Use: The instrument is intended to be used in a central research facility for studies in materials science, chemistry, biology and physics. For example, in materials science and engineering, it will be used to study shape–memory metallic alloys, aluminum alloys for automotive uses, porous ceramic thin films and strained Si substrates for microelectronic devices, polymer nanocomposites, characterization of ion beam–solid interaction, optoelectronic thin films for solid state lighting and photovoltaic applications, and ceramic materials for low temperature solid oxide fuel cells. Application accepted by Commissioner of Customs: February 14, 2006.

Docket Number: 06–005. Applicant: University of Maryland, Materials Science and Engineering Department, Kim Building, Room 1237, College Park, MD 20742. Instrument: Electron Microscope, Model JEM–2100F. Manufacturer: JEOL Ltd., Japan. Intended Use: The instrument is intended to be used to characterize nanomaterials and nanocomposites at the atomic level. These include semiconductor nanostructures, polymeric materials, metal nanoparticles, ferroelectric/ferromagnetic oxide nanocomposites and semiconductor nanowires. Properties of materials examined include crystal structure and quality of material, structural defects, and morphology using techniques of electron diffraction, high resolution lattice imaging, bright/dark field imaging and obtaining electron diffraction patterns and images of areas as small as a few nanometers in diameter. The instrument will also be used in courses and for conducting individual graduate research projects. Application accepted by Commissioner of Customs: February 8, 2006.

**Gerald A. Zerdy,**

*Program Manager, Statutory Import Programs Staff.*

[FR Doc. E6–2988 Filed 3–1–06; 8:45 am]

**BILLING CODE 3510–DS–S**

## DEPARTMENT OF COMMERCE

### International Trade Administration

#### **Villanova University, et al., Notice of Consolidated Decision on Applications, for Duty–Free Entry of Electron Microscopes**

This is a decision consolidated pursuant to section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Suite 4100W, Franklin Court Building, U.S. Department of Commerce, 1099 14th Street, NW., Washington, DC.

Docket Number: 05–058. Applicant: Villanova University, Villanova, Pa. Instrument: Electron Microscope, Model H–7600–2 TEM. Manufacturer: Hitachi High–Technologies Corp., Japan. Intended Use: See notice at 71 FR 4895, January 30, 2006. Order Date: February 23, 2005.

Docket Number: 05–062. Applicant: University of Texas Medical Branch at Galveston, Galveston, TX. Instrument: Electron Microscope, Model JEM–2200FS. Manufacturer: JEOL Ltd., Japan. Intended Use: See notice at 71 FR 2024, January 12, 2006. Order Date: February 23, 2005.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered. Reasons: Each foreign instrument is a conventional transmission electron microscope (CTEM) and is intended for research or scientific educational uses requiring a CTEM. We know of no CTEM, or any other instrument suited to these purposes, which was being manufactured in the United States either at the time of order of each instrument OR at the time of receipt of application by U.S. Customs and Border Protection.

**Gerald A. Zerdy,**

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[FR Doc. E6–2987 Filed 3–1–06; 8:45 am]

**BILLING CODE 3510–DS–S**